


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590209	<b>Applicant(s)/Patent Under Reexamination</b>  NAVEN ET AL.
	<b>Examiner</b>  IQBAL ZAIDI	<b>Art Unit</b>  2464

SEARCHED			
Class	Subclass	Date	Examiner
370	230, 503	08/11/09	iz
709	203	08/11/09	iz
370	230-253, 503	03/08/2010	iz
370	230-253, 503	08/20/2010	iz
370	229-238, 252-253, 389-427, 466-473	04/05/2011	iz
709	235	04/05/2011	iz
370	229-238, 252-253, 389-427, 466-473	10/17/2011	iz
709	35	10/17/2011	iz

SEARCH NOTES		
Search Notes	Date	Examiner
370(text search only- see search history)	08/10/09	iz
EAST(USPAT, USPGPUB, EPO, USOCR, FERS, JPO, DERWENT	08/10/09	iz
Inventor and assignee search in EAST- see search history, Google, IEEE	08/10/09	iz
370(text search only- see updated search history)	03/08/2010	iz
Inventor and assignee search in EAST- see search history, Google, IEEE	03/08/2010	iz
EAST(see updated search)	08/18/2010	iz
Google, IEEE	08/18/2010	iz
EAST(see updated search)	04/05/2011	iz
Google, IEEE	04/05/2011	iz
EAST(see updated search)	10/17/2011	iz
Google, IEEE	10/17/2011	iz

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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